PTO/SB/08A
Approved for use through 10/31/99. OMB 0651-0031
Patent and Trademark Office: U.S. DEPARTMENT OF COMMERCE

							COMPLETE IF KNOWN					
Substinge	for form	1449A/PT	0				Application Number 09/945,167					
10188	INV	ORM	ATION D	ISCL	osu	RE	Confirmation Number		1582			
`	ATEM	ENT BY	APPL	IÇAI	NT	Filing Date		August 30, 2001				
APR_0 + 2000A	Ma	se as m	any sheets	as nece	essary)	First Named Inventor Group Art Unit		Ulrich C. Boettiger			
パバトエ	Ley-	U										
200	7840-1194					T	Examiner Name		Not yet assigned 108298543US		<u> </u>	
4084	1					2	Attorney Docket No.		108298543US		\$ / _	
<u></u>					· ·	U.S. PATENT I	DOCUMENT	<u>S</u>		Page Company	<u>/</u>	
•EXAMINER INITIALS				ind Code f known)		Name of Patentee or of Cited Docum	, approved		Publication of Cited Document	Where Relevant Passages or Relevant Figures Appear	,	
	AA U.S. Application No. 09/993,053 (Atty Docket No. 108298546US)				Boet	ttiger et al.		Filed	11/05/01			
	АВ	No. (Atty	Application 09/945,31 Docket N 98547US)	16	Boettiger et al.				08/30/01			
DRE	AC	4,988	,188		Ohta				01/29/91			
DBE	AD	5,142	_ _	MacDonald et al.			08/25	/92	***			
DBE	AE	5,194		Nishi				03/16/93				
DBE	AF	5,436		Hayano et al.				07/25/95				
DBE	AG	5,602		Miya	azaki et al.		03/16/93 07/25/95 02/11/97			<u>``</u>		
DBG	AH	5,907		Mak	inouchi		05/25	/99 	00			
DBE	AI	5,969		Mak	inouchi	10/19/99						
PBC	AJ	6,084	,244	_	Saik	i et al.	07/04/00		/00			
DISE	AK	6,188	,464 B1	_	Mak	inouchi			/01			
	AL			<u> </u>				<u> </u>	_	<u> </u>		
					FOI	REIGN PATEN	T DOCUME	NTS	_	D. O.L. Li. MA	\rightarrow	
*EXAMINER INITIALS	Cite No.	Kii			Code		постирующи			Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	Т	
	ΑМ	-JP	1123123	4		ASAHI OPTICA	AL CO. LTD	- 8,	/27/99	Abstract Only		
	AN	<u> </u>			1						\sqcap	
	AO										\prod	
	ΑP				1		··· •··				\square	
	AQ										П	
	AR											
						T-NON PATE				· · · · · · · · · · · · · · · · · · ·		
•EXAMINER INITIALS	Cite No.		Include name	of the aut	hor (in (CAPITAL LETTERS),	title of the article (v	when appr	opriate), title of the i	tem (book, magazine, untry where published.	Т	
INITIALS						"Micronic and F					H	
	AS		c 1999 (1 p			The state of the s	The state of the s		- Julian Goner		\Box	
									-			

PTO/SB/08A

Approved for use through 10/31/99. OMB 0651-0031

						Patent and Trad	Approved for use through 10/31/99. OMB 0651-0031 lemark Office: U.S. DEPARTMENT OF COMMERCE				
						COMPLETE IF KNOWN					
	Substitute fo	r form	1449A/PTO			Application Number 09/945,167					
		INF	RMATI N	I DISCL SUR	E	Confirmation Number	1582				
/	IPE	ST	ATEMENT B	Y APPLICAN	IT	Filing Date	August 30, 2001				
'C	70%	•		ets as necessary)		First Named Inventor	Ulrich C. Boettiger				
	3 7000	`\ L`	,	•		Group Art Unit	1756				
	(use as many sneets as necessary)					Examiner Name	Not yet assigned				
3	Sheete	7	2	of	2	Attorney Docket No.	108298543US				
7	FUKUDA, H. et al., "Improvement of defocus tolerance in a half-micron optical lithography by the focus latitude enhancement exposure method: Simulation and experiment," J. Vac. Sci. Technol B. Vol. 7 No. 4, Jul/Aug 1989, pp. 667-674, 8 pages.										
	Texas Instruments Incorporated, "What the Industry Experts Say About Texas Instruments Dig MicroMirror Display (DMD) Technology," 6/94, (2 pages).										
	EXAMINE	R				DATE CONSIDERED					
	DR	2 M	250								
	*EXAMINE			•		s in conformance with MI	•				
	l		conformance and no	ot considered. Include	copy of this form with	n next communication to appli	icani(s).				

RECEIVED
TO 1700

PTU/SB/08A

Approved for use through 10/31/99. OMB 0651-0031
Patent and Trademark Office: U.S. DEPARTMENT OF COMMERCE

							Patent ar	nd Trade	mark Office: U.S. D	EPARTMENT OF COMMER	CE_
						COMPLETE IF KNOWN					
Substitut	e for for	n 1449A/P7	го				Application Number		09/945,167		
	IN	FORM	ATION	DISCLO	SUR	RE	Confirmation Number		1582		
OIB	TATEN	IENT BY	/ APPLI	CAN	T	Filing Date		August 30, 2001			
in.	(use as r	nany sheet	ts as nece.	ssary)		First Named Inventor		Ulrich C. Boettiger			
2 1 2000 0							Group Art Unit		1756		
- Lang	2002 =)						Examiner Name Attorney Docket No.		Not yet assigned 108298543US		
Sheet	<u>-</u>	1 of		11							
PADEMARK OF					J	J.S. PATENT	DOCUMENTS				
*EXAMINER Cite		U.S. Patent Document				Name of Patentee		Date o	f Publication of Cited	Pages, Columns, Lines, Where Relevant Passages or	r
INITIALS	No.	NUMBE	NUMBER Kind Code (if known)		of Cited Docu		ument	Document		Relevant Figures Appear	
DEC	AA	5,300,	971		Kud	lo	04		5/94	P	
in 2	AB			_				11/0	1/07	REC	
USE	<u> </u>	5,684,	,300		Stanton			11/04/97			
256	AC	6,285,	440	B1	Takahashi			09/04	1/01	EIVE	
	AD	6,392,	740	BI	Shiraishi et al.			05/21/02		F 23 YE	
	AE	<u> </u>		_	-					RO 0	
	-			_	 			 	 ;	<u> </u>	
	AF								ti or.	3	
	AG	i		1	}			1			
	AH										
	AI	 									
	<u> </u>	և		1				<u> </u>		<u> </u>	
					FOR	EIGN PATEN	IT DOCUMEN	ITS		Pages, Columns, Lines, Where	
*EXAMINER INITIALS	Cite No.					Name of Patentee or Applicant of Cited Document			Relevant Passages or Relevant		
INITIALS	Office Number				0.00			Cited Document	Figures Appear	1	
	ΔJ		}		}	_					
	AK										Г
	AL		 	···	1						+
			 			 					╁
	AM				↓ _						<u> </u>
	AN										1
			OTHER	PRIOR	AR	Γ-NON PATE	NT LITERATI	URE I	OCUMENTS	<u> </u>	
•EXAMINER	Cite		Include nam	e of the auth	or (in C	APITAL LETTERS)	, title of the article (wi	nen appr	opriate), title of the ite	em (book, magazine,	Т
INITIALS	No.	·	journal, seria	l, symposium	, catalo	og, etc.), date, page(s),	volume0issue number	r(s), pub	lisher, city and/or cou	ntry where published.	┼
	AO										ļ
	AP	•									1
											1
	AQ										
EXAMINE							DATE CONS	IDER	ED		
DE	5 () A4	1	2-	-			10/2	3 /	a 5		
* EXAMINI			reference o	onsidered 1	whether	or not criteria in	in conformance w			ine through citation if no	, in
							next communication to			duoden chanon n no	